Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/749,670	KIM ET AL.	
Examiner	Art Unit	
Dannie Bengrie	2624	

SEARCHED			
Class	Subclass	Date	Examiner
732	144-150	5/17107	
	141	12/18/07	DIS
		•.	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
`			
,			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
(Codated)	DATE	EXMR	
(Fast, all dB)	5/17107	DR	
	(6/4/07)		
	[12/13/07	)(DR)	
IEE 5-inspection	5/17/07	PR	
(neat) water and			
threshold #-			
TEEF- threshold	1015/07	吹	
LNEWY defect			
CHEAT image	12/13/07	DR	
cnew-> (upper or			
cnew-> (upper or lower) and different or subtract +) and			
defect-		-	
	;		
•	!		